



PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1427		SERIAL NO. 09/559,903		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yin et al.				
				FILING DATE April 26, 2000		GROUP 2815		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
AW	AA	US 2001/0003064 A1	06-2001	Ohno			Dec. 4, 2000	
AW	AB	US 2003/0013311 A1	01-2003	Chang et al.			Jul. 3, 2001	
	AC							
	AD							
	AE							
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER				/Allan Wilson/				
				DATE CONSIDERED 05/03/2006				
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Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET  
M12-1477SERIAL NO.  
E146567LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Micron Technology, Inc.FILING DATE  
Filed Herewith 4/26/00

GROUP 2815

## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
YK	AA 4,954,867	09/04/90	Hesske	257	639	
YK	AB 5,441,797	08/15/95	Hagan et al.	428	209	
YK	AC 5,472,827	12/05/95	Ogawa et al.	430	315	
YK	AD 5,674,356	10/01/97	Nagayama	438	694	
YK	AE 5,710,067	01/20/98	Foster et al.	438	636	
YK	AF 5,731,242	03/24/98	Parut et al.	438	546	
YK	AG 5,741,721	04/21/98	Stevens	439	396	
YK	AH 5,759,755	06/02/98	Park et al.	430	512	
YK	AI 5,838,052	11/17/98	McTeer	257	437	
	AJ					
	AK					

## FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
YK	AL JP06067019A	1/14/91	Japan (Abstract)	-	-		
YK	AM 0 471 185 A2	2/14/92	EPO	-	-		
YK	AN 0 588 087 A2	3/24/94	EPO	-	-		
YK	AO 0 588 087 A3	3/24/94	EPO	-	-		
	AP						

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

YK	AR	ARTICLE: Beacher, C. et al., "Dielectric antireflective coatings for DUV lithography", Solid State Technology (March 1997), pp. 109-114.
YK	AS	ARTICLE: Damann, R. R. et al., "Dependence of Optical Constants of AZ® BARL™ Bottom Coating on Back Conditions", SPIE Vol. 3049 (1997), pp. 963-973.
YK	AT	TEXT: Heavens, O. S., "Optical Properties of Thin Solid Films", pp. 48-49.

EXAMINER

J. E. Schmitt

DATE CONSIDERED

2/28/01

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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SHEET 4 of 4

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1427		SERIAL NO. Filed Herein	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		09/559903	
				FILING DATE Filed Herein		4/26/00 GROUP 2815	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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		Document Number	Date	Country	Class	Subclass	Translation Yes No
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	AN						
	AO						
	AP						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
9/22	AR			TEXT: Jenkins, P. et al., "Fundamentals of Optics", Properties of Light, pp. 9-10.			
9/22	AS			TEXT: Wolf, S. et al., "Silicon Processing for the VLSI Era", Vol. 1, pp. 437-441.			
	AT						
EXAMINER		9/22 Elyot		DATE CONSIDERED 9/28/01			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Sheet 1 of 3

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1427		SERIAL NO. 06559,903	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhigang Yin et al.		FILING DATE April 26, 2000	
				GROUP 2816			

  

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
JK	AA 5,472,829	12/95	Ogawa	430	325		
JK	AB 5,591,566	01/97	Ogawa	430	325		
JK	AC 5,641,607	06/97	Ogawa et al.	430	212.15		
JK	AD 5,648,202	07/97	Ogawa et al.	430	325		
JK	AE 5,677,111	10/97	Ogawa	430	313		
JK	AF 5,670,297	09/97	Ogawa et al.	430	318		
JK	AG 5,698,352	12/97	Ogawa et al.	430	14		
JK	AH 5,831,321	11/98	Nagayama	257	412		
JK	AI 5,034,348	07/91	Hartwick et al.	438	453		
JK	AJ 6,008,124	12/99	Schiguchi et al.	438	653		
JK	AK 5,340,621	08/94	Matsumoto et al.	427	571		
JK	AL 5,600,165	02/97	Tanamoto et al.	257	323		

  

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
JK AM 0-778496 A2/A3	06/97	EPO	-	-	Yes	No	
JK AN 9-55351	02/97	Japan	-	-	Yes	No	
JK AO					Yes	No	
JK AP					Yes	No	
JK AQ					Yes	No	

  

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
JK	AR	McKenzie, D. et al. "New Technology for PACVD", Surface and Coatings Technology 82 (1996), pp. 326-333.
JK	AS	Shibata, Noboru, "Plasma-Chemical Vapor-Deposited Silicon Oxide/Silicon Oxynitride Double-Layer Antireflective Coating for Solar Cells", Jap. Joun. of Applied Physics, Vol. 30, No. 5, May 1991, pp. 997-1001.
	AT	

  

EXAMINER JK Ely	DATE CONSIDERED 9/20/01
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1427		SERIAL NO. 09/559,903	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yin et al.		FILING DATE April 26, 2000	
				GROUP 2815			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
ym	AA 5,968,324	07/99	Cheng et al.	204	19228		
ym	AB 5,872,385	02/99	Teh et al.	257	437		
ym	AC 5,883,011	09/99	Lio et al.	2438	247		
ym	AD 5,960,289	09/99	Tsui et al.	238	275		
ym	AE 6,020,243	02/00	Wallace et al.	238	287		
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
ym	AM US 99/20029	08/99	PCT Search Report				
ym	AN US 99/20030	08/99	PCT Search Report				
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER 9/20/01				DATE CONSIDERED 9/20/01			

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1427		SERIAL NO. 05539,903	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhang Yie et al		GROUP 2815	
				FILING DATE April 26, 2000			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
Jee	AA	App. 09/030,618 as filed and amended	2/25/98	Holscher			02/98
	AB						
	AC						
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation Yes No	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER Jee			DATE CONSIDERED 2/20/01				

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Form PTO-1413		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 2003-1417		SERIAL NO. 09-277,703	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Fujitsu, Ltd. et al.			
FILING DATE April 24, 2000				GROUP 2115			
U.S. PATENT DOCUMENTS							
Examiner Label	Document Number	Date	Name	Class	Subclass	Filing Date (If Applicable)	
782	AA	6,133,618	10-2000	Software			
	AB	5,994,317	11-1999	Ng			
	AC	5,932,529	11-1999	Kakumoto et al.			
	AD	5,147,388	03-1998	Kakumoto et al.			
	AE	5,639,687	06-1997	Roman et al.			
	AF	5,198,333	03-1996	Liu			
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
	AM					Yes	No
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Periodical Pages, Etc.)							
781	A	Walt, R. "Silicon Processing for the VLSI Era," Vol. 1, pp. 67-113.					
781	AS	Walt, R. "Silicon Processing for the VLSI Era," Vol. 1, pp. 43-82 and 111.					
EXAMINER P. J. H. H.				DATE CONSIDERED 2/17/04			
*EXAMINER: Indicate if reference considered, whether or not citation is in conformity with MPEP 609; Draw line through citation if not in conformity and not considered. Include copy of this form with oral communication to applicant.							

F. I. 979950463

Form PTO-140		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MFD-147		SERIAL NO. 09792.00	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Edging Tm et al.			
				FILING DATE April 24, 2003		GROUP 2815	
U.S. PATENT DOCUMENTS							
Examiner Initials	Document Number	Date	Title	Class	Subject	Filing Date If Appropriate	
JK	AA US 2001/003004 A1	06-2001	Orin			Dec. 4, 2000	
AL	AB US 2001/012311 A1	01-2002	Cheng et al			Oct. 3, 2001	
	AC						
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subject	Translation	
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JKS/hrs				2/17/04			

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